MOSFET – Power, N-Channel, SUPERFET III, Easy Drive

650 V, 19 A, 165 m Ω

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provides superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET III MOSFET Easy drive series helps manage EMI issues and allows for easier design implementation.

Features

- 700 V @ $T_J = 150^{\circ}C$
- Typ. $R_{DS(on)} = 140 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 35 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 345 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

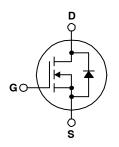
- Computing / Display Power Supplies
- Telecom / Server Power Supplies
- Industrial Power Supplies
- Lighting / Charger / Adapter



ON Semiconductor®

www.onsemi.com

V _{DS}	R _{DS(ON)} MAX	I _D MAX
650 V	165 m Ω @ 10 V	19 A

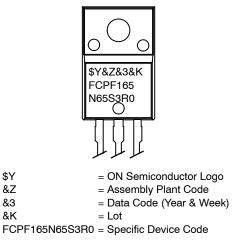


N-CHANNEL MOSFET



TO-220F-3LD CASE 340BF

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter		Value	Unit
V _{DSS}	Drain to Source Voltage		650	V
V _{GSS}	Gate to Source Voltage	– DC	±30	V
		– AC (f > 1 Hz)	±30	V
Ι _D	Drain Current:	– Continuous (T _C = 25°C)	19	А
		– Continuous (T _C = 100°C)	12.3	
I _{DM}	Drain Current:	Current: - Pulsed (Note 1)		А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		87	mJ
I _{AS}	Avalanche Current (Note 2)		2.7	A
E _{AR}	Repetitive Avalanche Energy (Note 1)		0.35	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		20	
PD	Power Dissipation	(T _C = 25°C)	35	W
	Derate Above 25°C		0.28	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		–55 to + 150	°C
ΤL	Maximum Lead Temperature for Soldering, 1/	8" from Case for 5 seconds	300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality shows be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 2.7 \text{ A}, R_G = 25 \Omega$, starting $T_J = 25 \text{ °C}$. 3. $I_{SD} \le 9.5 \text{ A}, \text{ di/dt} \le 200 \text{ A/}\mu\text{s}, \text{V}_{DD} \le 400 \text{ V}, \text{ starting } T_J = 25 \text{ °C}.$

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
FCPF165N65S3R0L	FCPF165N65S3R0	TO-220F	Tube	N/A	N/A	50 Units

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	3.56	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient, Max.	62.5	

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Parameter	Test Condition	Min.	Тур.	Max.	Unit
ACTERISTICS		•			
Drain to Source Breakdown Voltage	V_{GS} = 0 V, I _D = 1 mA, T _J = 25°C	650			V
Drain to Source Breakdown Voltage	V_{GS} = 0 V, I _D = 1 mA, T _J = 150°C	700			V
Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		0.64		V/°C
Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
	V_{DS} = 520 V, T_{C} = 125 °C		1.39		
Gate to Source Leakage Current	$V_{GS}=\pm 30~\text{V}, ~V_{DS}=0~\text{V}$			±100	nA
	CTERISTICS Drain to Source Breakdown Voltage Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current	OPEN PER	CTERISTICS $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$ 650 Drain to Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 150^{\circ}\text{C}$ 700 Breakdown Voltage Temperature Coefficient $I_D = 1 \text{ mA}, \text{Referenced to } 25^{\circ}\text{C}$ 700 Zero Gate Voltage Drain Current $V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, T_C = 125^{\circ}\text{C}$	OTERISTICSDrain to Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$ 650Drain to Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 150^{\circ}\text{C}$ 700Breakdown Voltage Temperature Coefficient $I_D = 1 \text{ mA}, \text{Referenced to } 25^{\circ}\text{C}$ 0.64Zero Gate Voltage Drain Current $V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ 1.39	CTERISTICSDrain to Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$ 650Drain to Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 150^{\circ}\text{C}$ 700Breakdown Voltage Temperature Coefficient $I_D = 1 \text{ mA}, \text{Referenced to } 25^{\circ}\text{C}$ 0.64Zero Gate Voltage Drain Current $V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ 1 $V_{DS} = 520 \text{ V}, T_C = 125^{\circ}\text{C}$ 1.39

ON CHARACTERISTICS

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 0.41$ mA	2.5		4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V_{GS} = 10 V, I _D = 9.5 A		140	165	mΩ
9 _{FS}	Forward Transconductance	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 9.5 \text{ A}$		12		S

DYNAMIC CHARACTERISTICS

C _{iss}	Input Capacitance	V_{DS} = 400 V, V_{GS} = 0 V, f = 1 MHz	1415	pF
C _{oss}	Output Capacitance		35	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	345	pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	48	pF
Q _{g(tot)}	Total Gate Charge at 10 V	$V_{DS} = 400 \text{ V}, \text{ I}_{D} = 9.5 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$	35	nC
Q _{gs}	Gate to Source Gate Charge	(Note 4)	8.3	nC
Q _{gd}	Gate to Drain "Miller" Charge		15	nC
ESR	Equivalent Series Resistance	F = 1 MHz	0.5	Ω

SWITCHING CHARACTERISTICS

t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 9.5 \text{ A},$	17	ns
t _r	Turn-On Rise Time	V _{GS} = 10 V, R _g = 4.7 Ω (Note 4)	16	ns
t _{d(off)}	Turn-Off Delay Time		43	ns
t _f	Turn-Off Fall Time		5	ns

DRAIN-SOURCE DIODE CHARACTERISTICS

۱ _S	Maximum Continuous Source to Drain Diode Forward Current			19	А
۱ _S	Maximum Pulsed Source to Drain Diode Forward Current			47.5	А
V _{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 9.5 \text{ A}$		1.2	V
t _{rr}	Reverse Recovery Time	$V_{DD} = 400 \text{ V}, \text{ I}_{SD} = 9.5 \text{ A},$	323		ns
Q _{rr}	Reverse Recovery Charge	di/dt = 100 A/µs	5.2		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

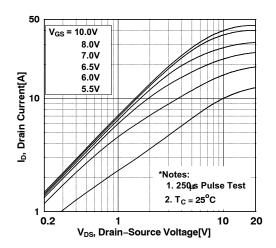


Figure 1. On–Region Characteristics

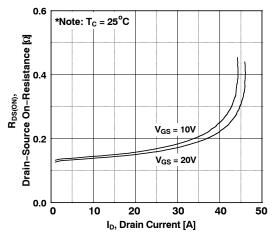


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

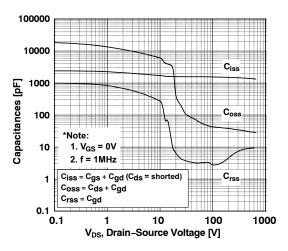


Figure 5. Capacitance Characteristics

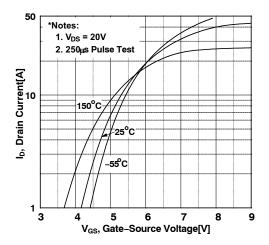


Figure 2. Transfer Characteristics

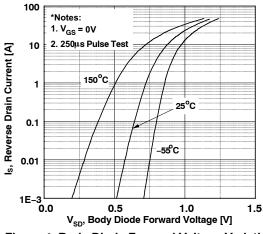


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

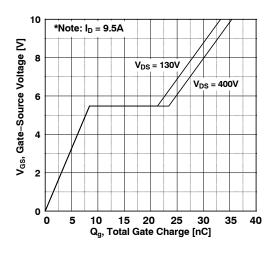


Figure 6. Gate Charge Characteristics

TYPICAL CHARACTERISTICS

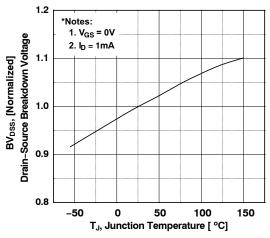


Figure 7. Breakdown Voltage Variation vs. Temperature

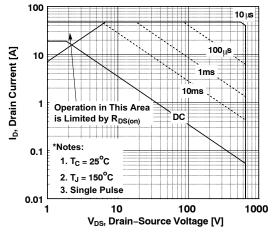


Figure 9. Maximum Safe Operating Area

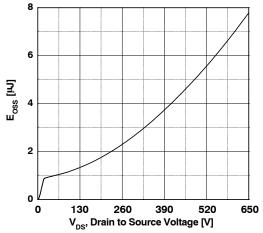


Figure 11. Eoss vs. Drain to Source Voltage

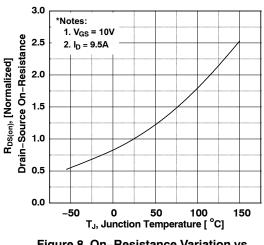


Figure 8. On–Resistance Variation vs. Temperature

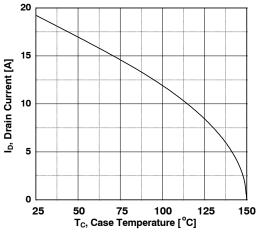


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL CHARACTERISTICS

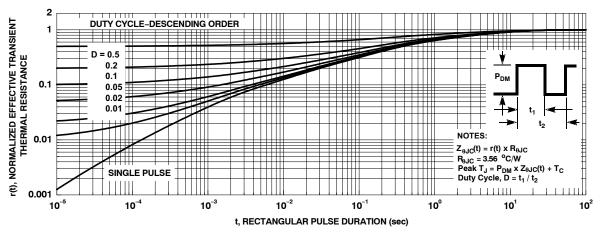
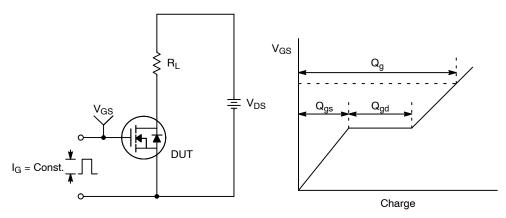


Figure 12. Transient Thermal Response Curve





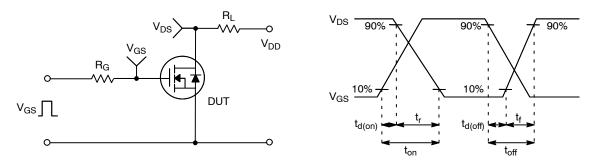


Figure 14. Resistive Switching Test Circuit & Waveforms

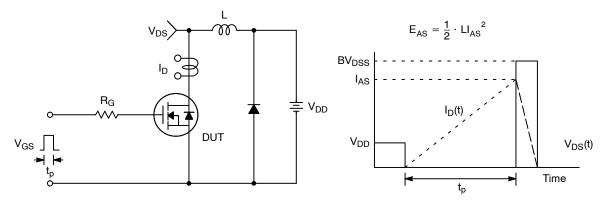


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

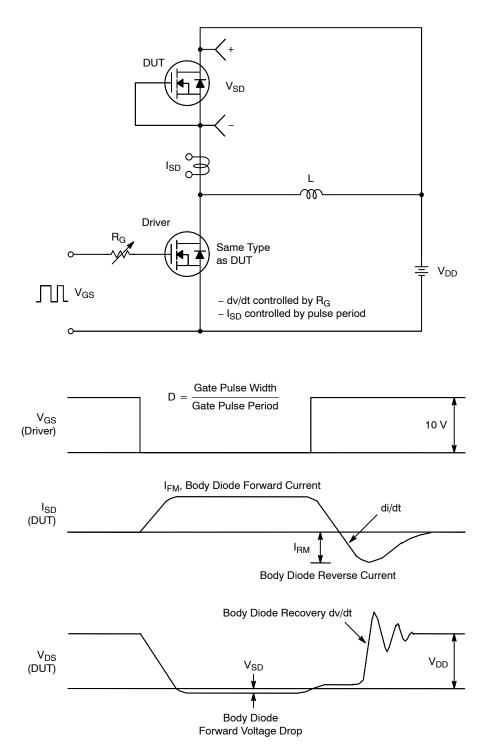


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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TO-220 FULLPAK 3LD CASE 340BF **ISSUE O** DATE 31 AUG 2016 10.30 Α 9.80 2.90 Ø3.40 3.00 2.50 6.60 6.20 3.00 ++2.60 B 19.00 1 X 45° <u>B</u> 15.70 15.00 3.30 B 3 1 2.70 (2.14) 1.20 0.90(2X) 2.30 10.70 10.30 B 0.60 0.40 0.90 (3X) 0.50 1.20 $\oplus 0.50$ M Α NOTES: 2.74 (2X) 2.34 A. EXCEPT WHERE NOTED CONFORMS TO EIAJ SC91A. DOES NOT COMPLY EIAJ STD. VALUE. C. ALL DIMENSIONS ARE IN MILLIMETERS. D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS. E. DIMENSION AND TOLERANCE AS PER ASME Y14.5-2009. <u>mn mm</u> 4.60 ПП 4.30

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